

x-correlation in wavelet domain for detection of stochastic gravitational waves

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Outline

- **Introduction**
- **Optimal cross-correlation**
- **Correlation tests**
- **Correlated noise**
- **robust x-correlation in wavelet domain**
- **Conclusion**

- **Stochastic Gravitational Waves**
 - from early universe or/and large number of unresolved sources

(GW energy density)/(closure density)

$$\Omega_{GW} < 10^{-5}$$

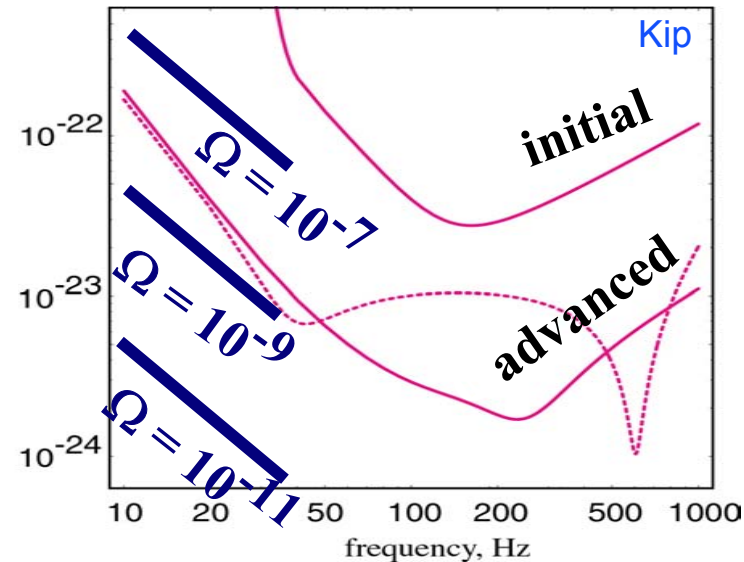
- **Detection of SGW**

- x-correlation of detector output signals $s_L(t)$ and $s_H(t)$

$$S = \int_0^T dt \int_0^T dt' s_L(t') s_H(t) Q(t-t', \Omega_L, \Omega_H)$$

- T – observation time, Q - optimal kernel

- Ω_H (Ω_L) is the orientation of H (L) interferometer



- **x-correlation in Fourier domain**

B. Allen and J.D. Romano,
Phys. Rev. D59, pp. 102001-102041, 1999

$$S = \int_{-\infty}^{\infty} df \tilde{s}_H(f) \tilde{s}_L^*(f) Q(f, \Omega_L, \Omega_H)$$

- **Optimal kernel:**

$$Q(f, \Omega_L, \Omega_H) = \frac{|f|^{-3} \Omega_{GW}(f) \gamma(f, \Omega_L, \Omega_H)}{P_L(f) P_H(f)}$$

- ✓ Ω_{GW} – SGW strength

- ✓ P_L, P_H - spectral densities of detector noise

- ✓ γ – detector overlap function (E. Flanagan, Phys. Rev. D48, 2389 (1993))

- **Questions:**

- What is the *distribution of S* if noise is not Gaussian?

Allen, Creighton, Flanagan, Romano, PRD 65, 122002, 2002

- What if *S* is affected by correlated noise? (LLO-Allegro)

- How *Q* is affected?

- **linear**

$$r = \frac{\sum_i (x_i - \bar{x})(y_i - \bar{y})}{\sqrt{\sum (x_i - \bar{x})^2} \sqrt{\sum (y_i - \bar{y})^2}}$$

use knowledge of r distribution
to perform the test

- parametric: no universal way to compute r distribution
- if data is not Gaussian, r is a poor statistics to decide
 - ✓ correlation is statistically significant
 - ✓ one observed correlation is stronger than another.

- **rank**

- non-parametric: exactly known r distribution
- CPU inefficient for large data sets

- **sign**

- primitive version of the rank test

- Sign transform: $u_i = \text{sign}(x_i - \hat{x})$ ± 1
 - \hat{x} - sample median of x
- Sign corr. statistic: $s_i = \text{sign}(x_i - \hat{x}) \cdot \text{sign}(y_i - \hat{y})$
- Correlation coefficient ρ : $\rho = \text{mean}(s_i)$
- Distribution of ρ (n - number of samples):
 - Gaussian (large n):
 - variance = $1/n$
$$P(n, \rho) \approx \sqrt{\frac{n}{2\pi}} \cdot \exp\left(-\frac{n\rho^2}{2}\right)$$
- very robust:
 - error from \hat{x} and \hat{y} $\sim 2/n^2$, much less than $\text{var}(\rho) = 1/n$ for large n
 - sensitivity? correlation between s_i samples?

- **Data:** simulated uncorrelated noise (n) + Gaussian signal (g)

$$x = n_x + g, \quad y = n_y + g$$

- **Test efficiency:** $\epsilon_s = r_s / r_L$

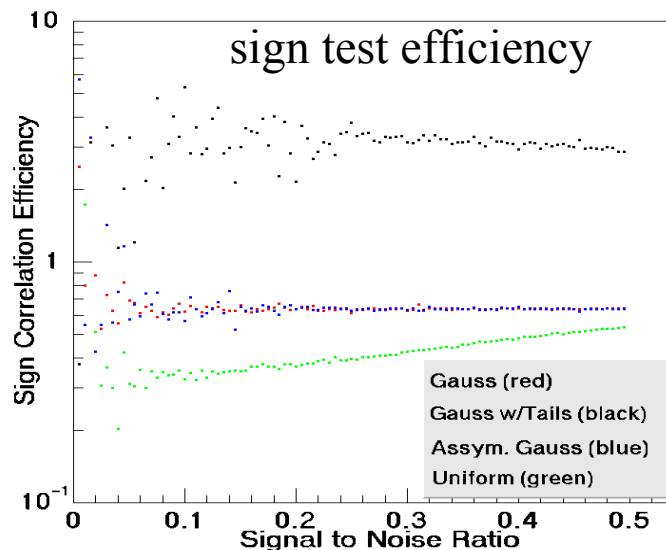
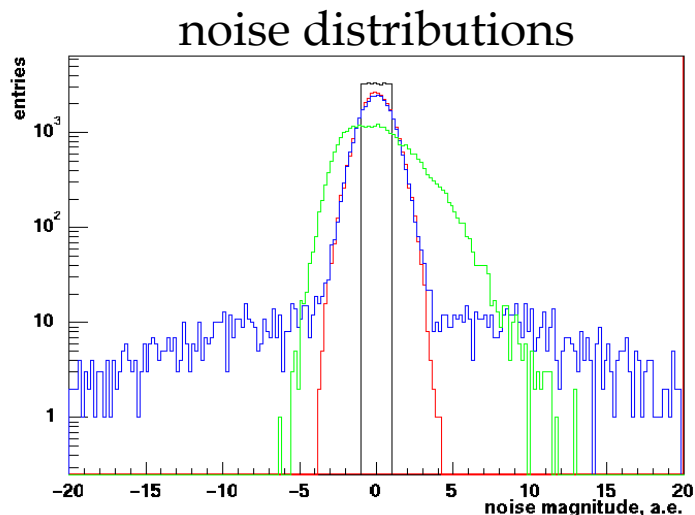
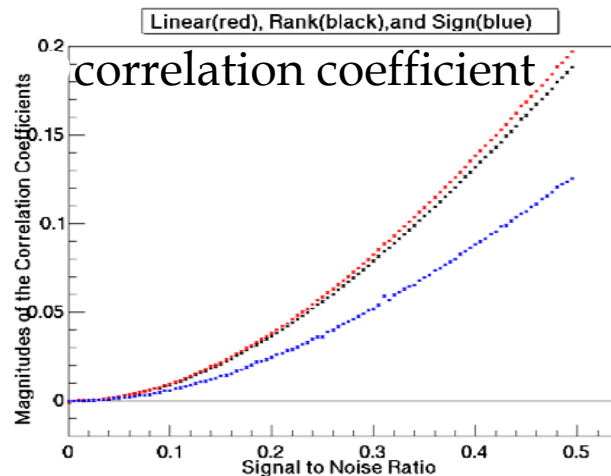
➤ for Gaussian noise

✓ rank test efficiency - 95%

✓ sign test efficiency - 64%

(2.5 loss of data)

➤ independent on SNR



- What does it mean that data is affected by correlated noise?

- ρ mean value is biased: $\langle \rho \rangle = \langle h_L + n_L, h_H + n_H \rangle = \langle h_L, h_H \rangle + \langle n_L, n_H \rangle$

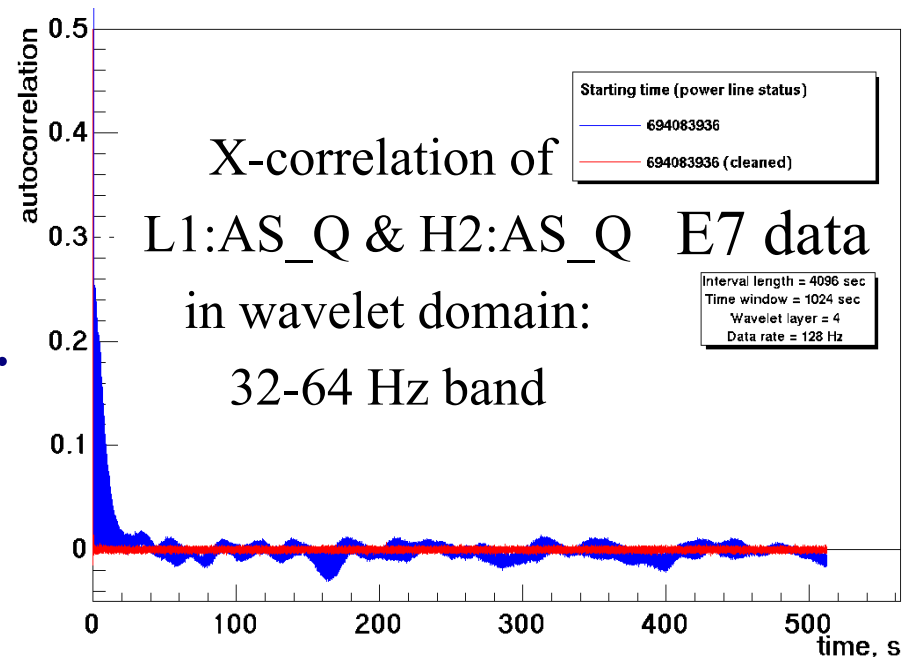
- ρ variance is affected: $\text{var}(\rho) = \langle \rho^2 \rangle - \langle \rho \rangle^2$

- Samples of sign correlation data $\{s_{ij}\}$ can be correlated

- $\{s_{ij}\}$ is generated by some random process $s(t)$ with autocorrelation function $a(\tau)$

- $a(\tau)$

- takes into account second order statistic $P(s_i, s_j)$
 - a measure of correlated noise.



- uncorrelated noise

- autocorrelation function: $a(0) = 1, a(\tau \geq \Delta t) = 0$

- null hypothesis: *data sets are not correlated*

- variance: $\text{var}_0(\rho) = \frac{1}{n}$

- correlated process with time scale $< T_s$

- autocorrelation function: $a(\tau < T_s) = a_n(\tau), a(\tau > T_s) = 0$

- null hypothesis: *data sets are not correlated at time scale $> T_s$*

- variance: $\text{var}_{T_s}(\rho) = \frac{1}{n} \nu, \nu = 1 + \frac{2}{n} \sum_{m=1}^{T_s / \Delta t} (n - m) a_n(m \Delta t)$

- calculation of $\text{var}(\rho)$, depending on the noise model.

- **variance ratio**

$$\nu(T_s) = \frac{\text{var}_{T_s}(\rho)}{\text{var}_0(\rho)}$$

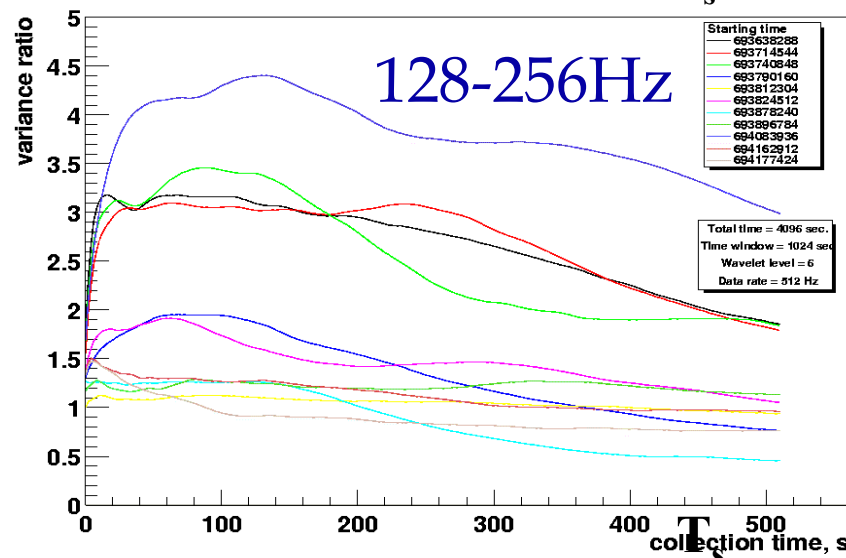
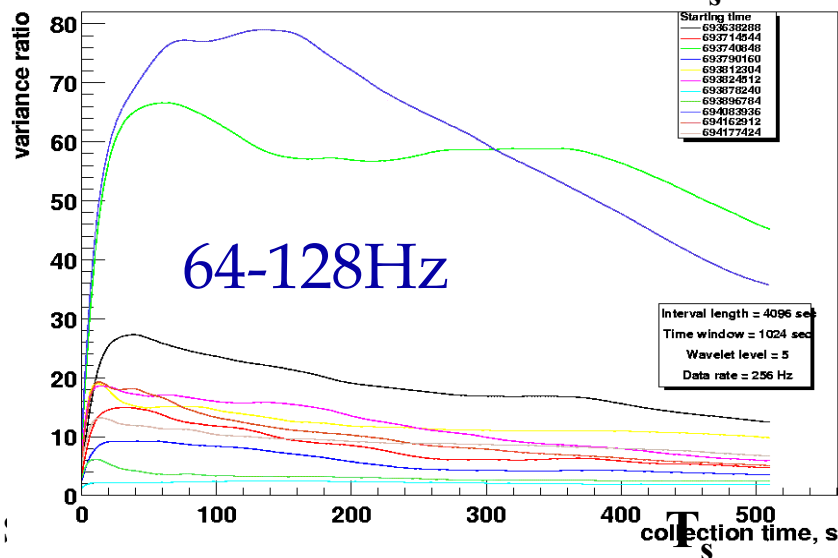
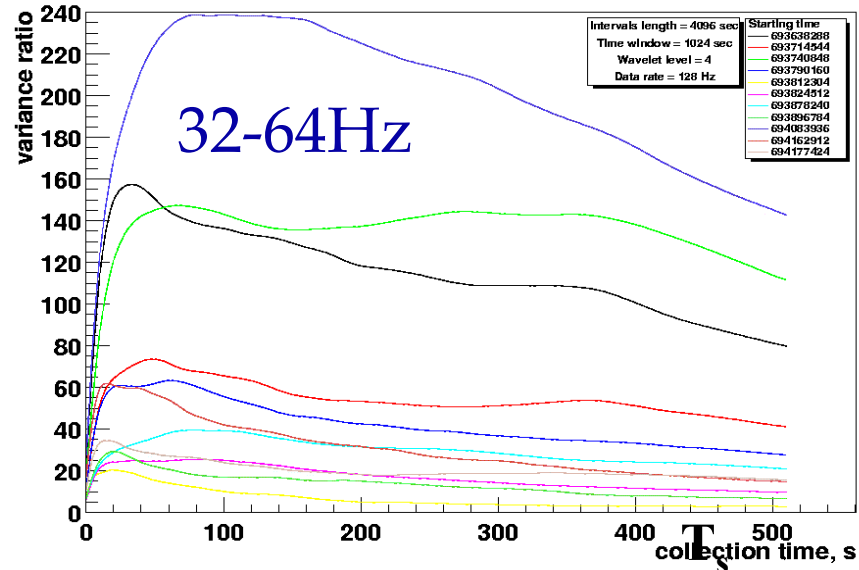
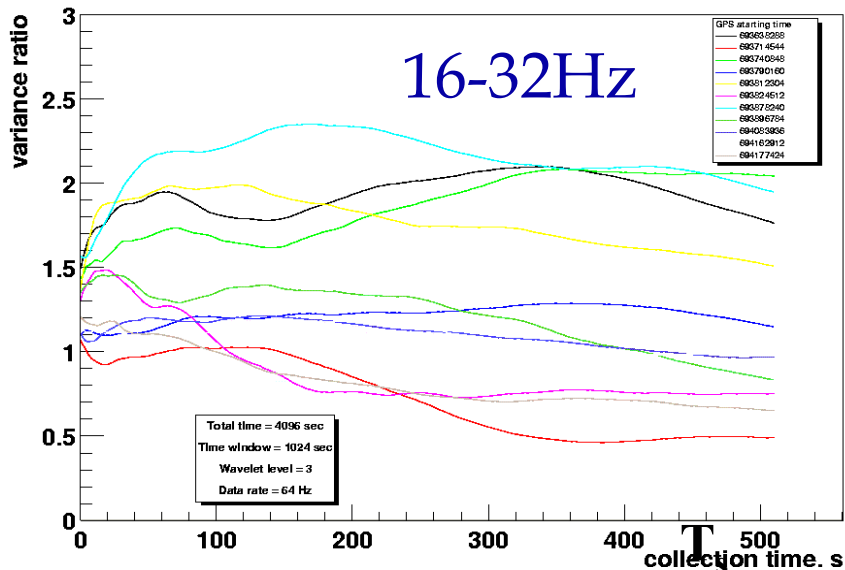
- ν is a **measure of correlated noise**, or quality of data.
- ν times more data needed to reach same CL as for uncorrelated noise.
- If ν is too large, the noise should be removed, if possible

- **correlation time**

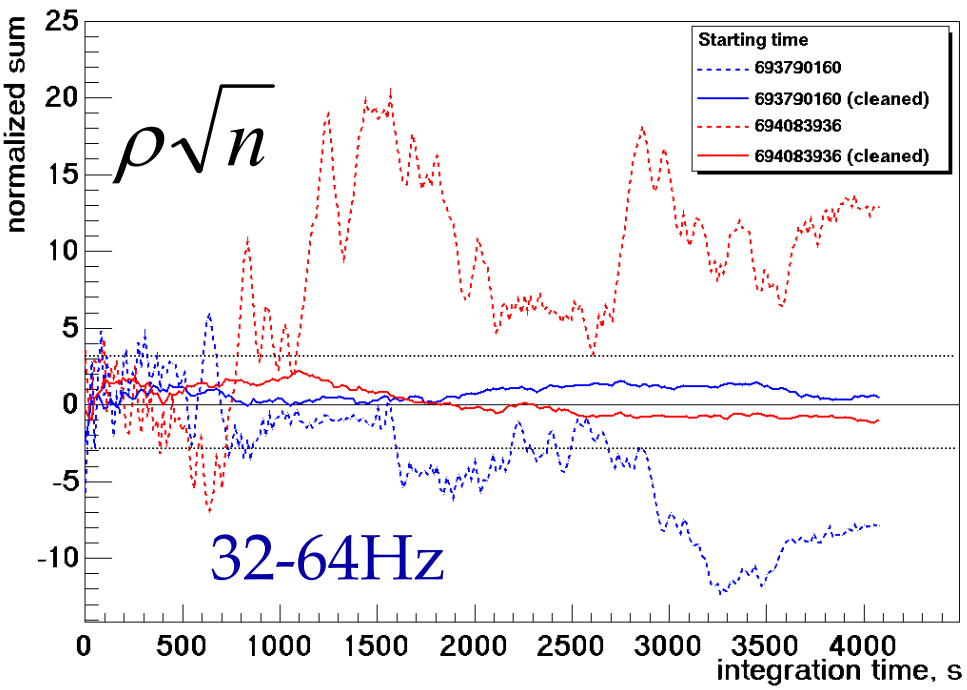
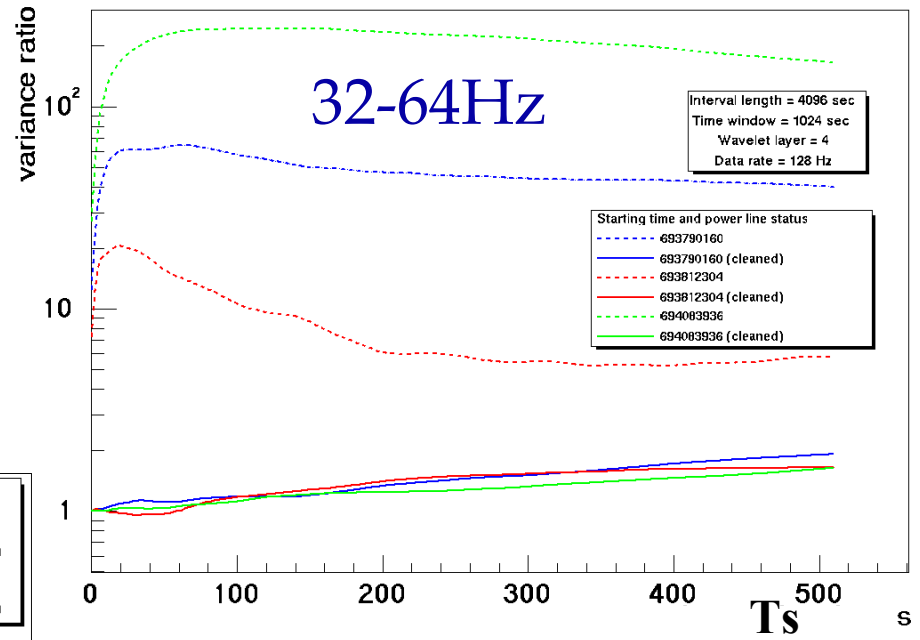
$$T_c = \int_0^\infty a(t) dt \approx \frac{\nu \Delta t}{2}$$

$$\text{var}(\rho) = \frac{1}{n} \nu \approx \frac{2T_c}{T},$$

- L1xH2: 11 data segments 4096 sec each (total 12.5 h of E7 data)



- QMLR method was used



$\pm 3 / \sqrt{n}$

dots - before
solid - after

- time-frequency representation of data in wavelet domain

➤ P_{mn} : n – scale (frequency) index, m – time index

- due to of locality of wavelet basis, wavelet layers are decimated time series.

$$x_L(t) = \sum_{k,l} p_{kl} \psi_{kl}(t)$$

- X-correlation

$$S = \sum_{nm} \sum_{k,l} p_{kl} q_{mn} I_{kl,mn}$$

$$x_H(t) = \sum_{n,m} q_{mn} \psi_{mn}(t)$$

$$I_{kl,mn} = \int_0^T dt \int_0^T dt' \psi_{kl}(t') \psi_{mn}(t) Q(t-t', \Omega_L, \Omega_H)$$

➤ Ψ_{nm} – basis of wavelet functions

- **x-correlation is a sum over wavelet layers**

- ✓ τ – time lag

- ✓ k – wavelet layer number

- ✓ N_k – number of samples in layer k

- ✓ $r_k(\tau)$ – correlation coefficients as a function of lag time τ

$$S = \sum_{k,\tau} N_k w_k(\tau) r_k(\tau)$$

- **$w_k(\tau)$ – optimal filter**

$$w_k(\tau) = \int_{-\infty}^{\infty} df |\Psi_k(f)|^2 |f|^{-3} \frac{\Omega_{GW}(f) \cdot \gamma(f, \Omega_L, \Omega_H)}{P_L(f) / \sigma_k^L \cdot P_H(f) / \sigma_k^H} \exp(-j2\pi f \tau)$$

- ✓ Ψ_k – Fourier image of mother wavelet for layer k

- ✓ γ – overlap reduction function

- ✓ σ_k^L, σ_k^H – noise *rms* in wavelet domain for detector L (H)

- ✓ $P(f)$ – noise PSD

- **Sign x-correlation**

$$S_s = \sum_{k,\tau} N_k \omega_k(\tau) \rho_k(\tau) \rightarrow$$

- $\rho_k(\tau)$ - sign correlation coefficients

- $\omega_k(\tau)$ - optimal filter

- **Variance of ρ**

$$\text{var}(\rho_k(\tau)) = \frac{1}{N_k} \nu_k(\tau)$$

- **optimal filter**

$$\omega_k(\tau) = \varepsilon_k \frac{w_k(\tau)}{\nu_k(\tau)} \leftarrow$$

- ε_k - sign correlation efficiency

- $\nu_k(\tau)$ - contribution from correlated noise

- $w_k(\tau)$ - optimal filter for linear correlation

$$V_s = \sum_i N_i \omega_i^2 \nu_i$$

$$\bar{\rho}_i = \lambda_i \Omega$$

$$\mu = \Omega \sum_i N_i \omega_i \lambda_i,$$

$$\frac{\partial(SNR^2)}{\partial \omega_i} = \frac{\partial(\mu^2 / V_s)}{\partial \omega_i} = 0,$$

$$\omega_i = \lambda_i / \nu_i$$

$$\bar{r}_i = w_i \Omega$$

$$\lambda_i = w_i \frac{\bar{\rho}_i}{\bar{r}_i} = w_i \varepsilon_i$$

$$i = (k, \tau)$$

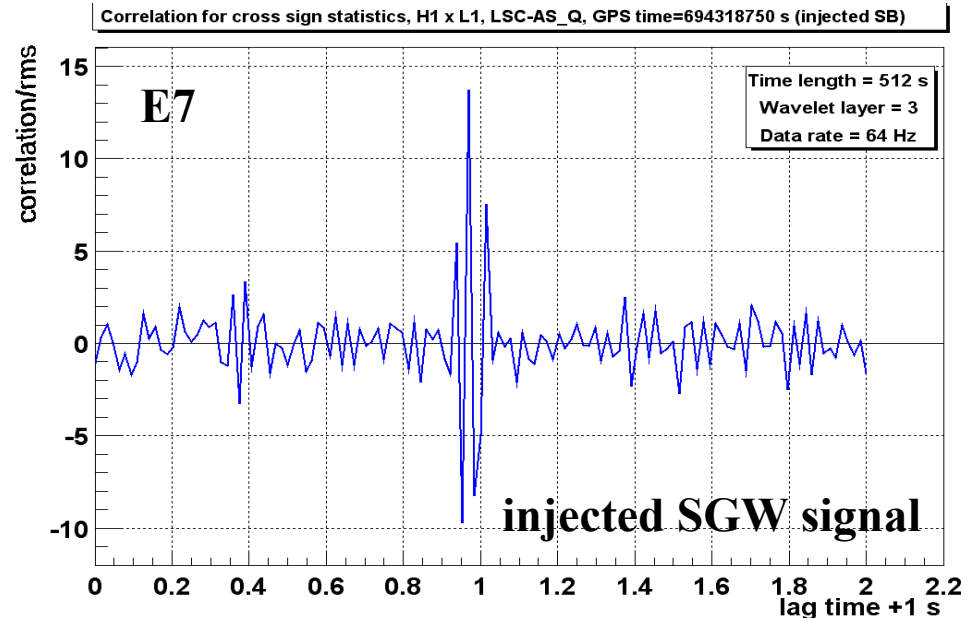
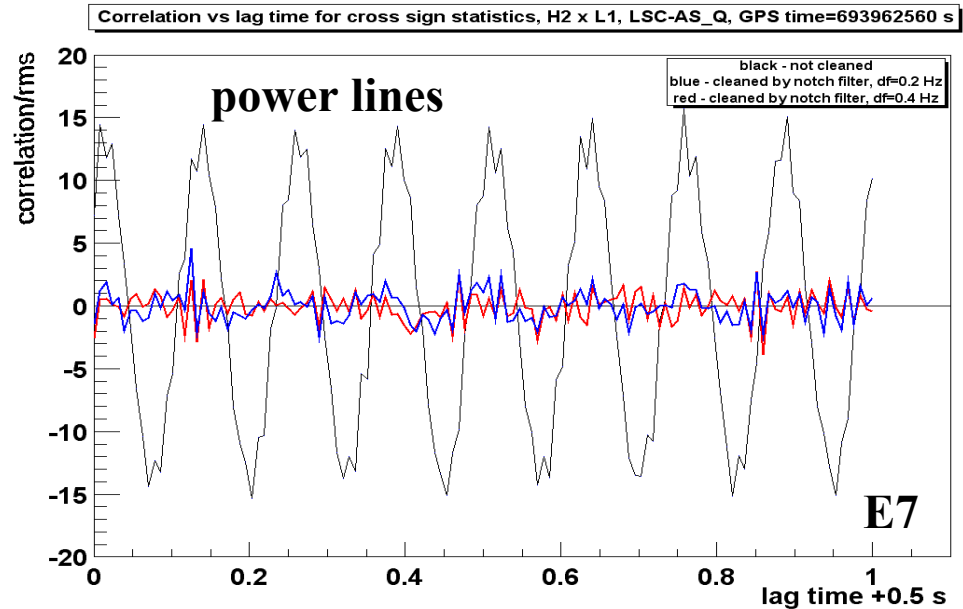
- Likelihood function

$$L = \sum_i \frac{N_i}{2V_i} (\rho_i - \bar{\rho}_i)^2 \quad i = (k, \tau)$$

- $\bar{\rho}_i$ depend on SGW and noise (parametric) models

$$\bar{\rho}_i(\Omega_{GW}, \Omega_n, \alpha, \beta, \dots)$$

- by measuring $\rho(\tau)$, SGW can be separated from correlated noise



- **Optimal filter**

$$\omega_k(\tau) = \frac{1}{V_k} \int_{-\infty}^{\infty} df |\psi_n(f)|^2 |f|^{-3} \frac{\Omega_{GW}(f) \cdot \gamma(f, \Omega_L, \Omega_H)}{A_L(f, k) \cdot A_H(f, k)} \exp(-j2\pi f\tau)$$

- **“noise amplitude”**

$$A_I(f, k) = \frac{P_I(f)}{\sigma_{kI} \sqrt{\epsilon_k}}$$

- **$A(f)$ is more robust than $P(f)$ if noise is non-stationary**

- **test with simulated noise**

➤ Gaussian noise (σ_g) + tail : total rms σ_n

σ_n / σ_g	P	A
1.0	0.45	0.0266
1.45	0.94	0.0274
2.31	2.40	0.0273

- **Cross-correlation & variance:**

$$S_s = \sum_{k,\tau} N_k \omega_k(\tau) \rho_k(\tau)$$

$$V_s = \sum_{k,\tau} N_k \omega_k^2(\tau) v_k(\tau)$$

$$\omega_k(\tau) = \varepsilon_k \frac{w_k(\tau)}{v_k(\tau)}$$

- **x-correlation expectation value:**

$$\mu = \Omega \sum_{k,\tau} N_k \omega_k^2(\tau) v_k(\tau) = \Omega V_s$$

- **signal to noise ratio:**

$$SNR = \Omega \sqrt{\sum_{k,\tau} N_k \omega_k^2(\tau) v_k(\tau)} = \Omega \sqrt{V_s}$$

- **confidence level:**

$$CL = \frac{1}{2} \operatorname{erf} \left(\frac{S_s}{\sqrt{V_s}} \right) \rightarrow \tilde{S}_s(95CL)$$

- **upper limit:**

$$\tilde{\Omega} = \frac{\tilde{S}_s(95CL)}{V_s}$$

- A robust correlation test with treatment of correlated noise is described. It allows:
 - **calculate x-correlation distribution if noise is not Gaussian**
 - **use a simple model of correlated noise**
 - **work for non-stationary noise**
- suggested method offers a good tool to estimate contribution from correlated noise.
 - **On E7 data it is shown how the noise affects the x-correlation.**
- we suggest to use sign x-correlation as a complementary method for setting SGW upper limit
 - **a very useful cross-check**
 - **uses $\rho_k(\tau)$ - signature of the cross-correlation**